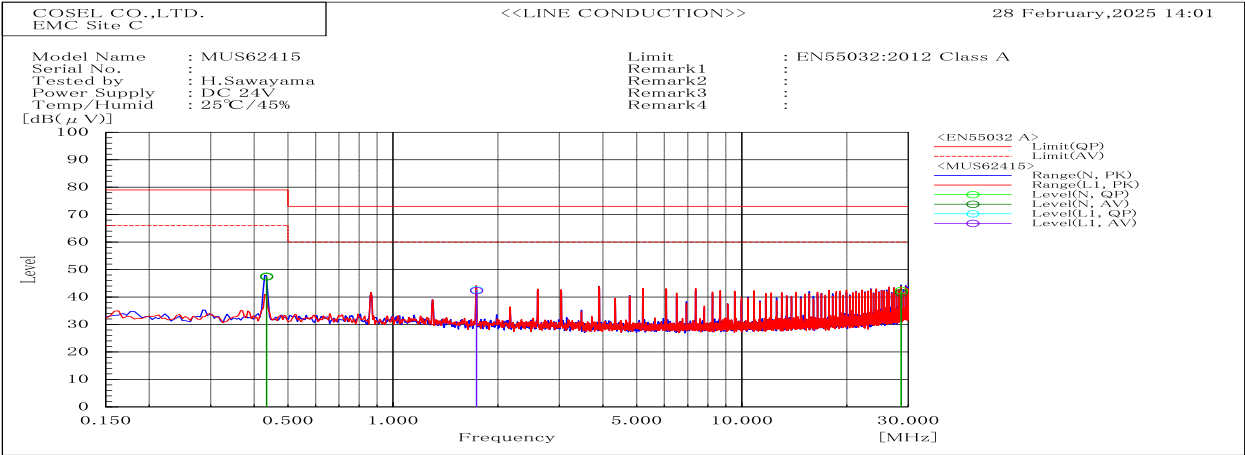
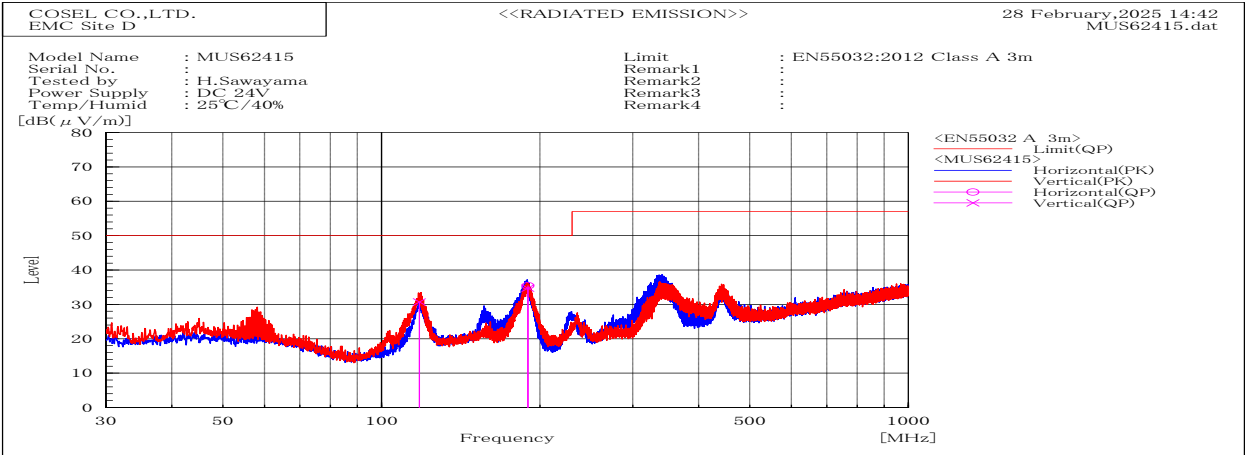


DATA SHEET		Date	28-Feb-25
Model	MUS62415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	H.Sawayama



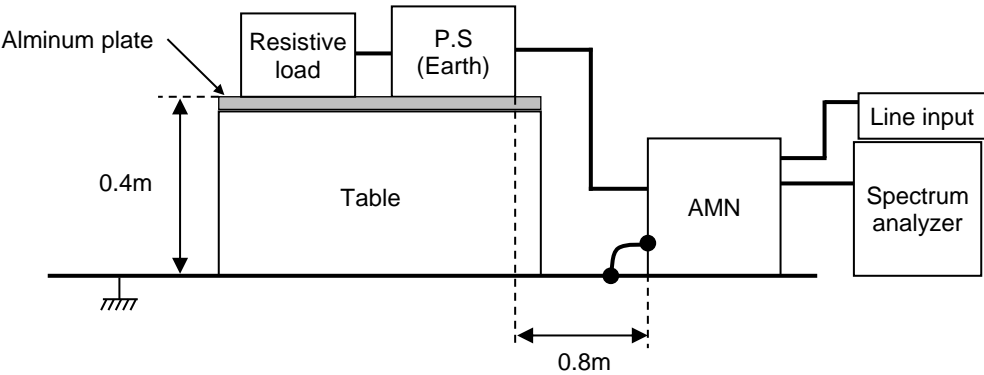
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.736	L1	42.6	42.3	73	60	30.4	17.7	Pass	
0.434	N	47.6	47.4	79	66	31.4	18.6	Pass	
28.648	N	42.4	41.5	73	60	30.6	18.5	Pass	



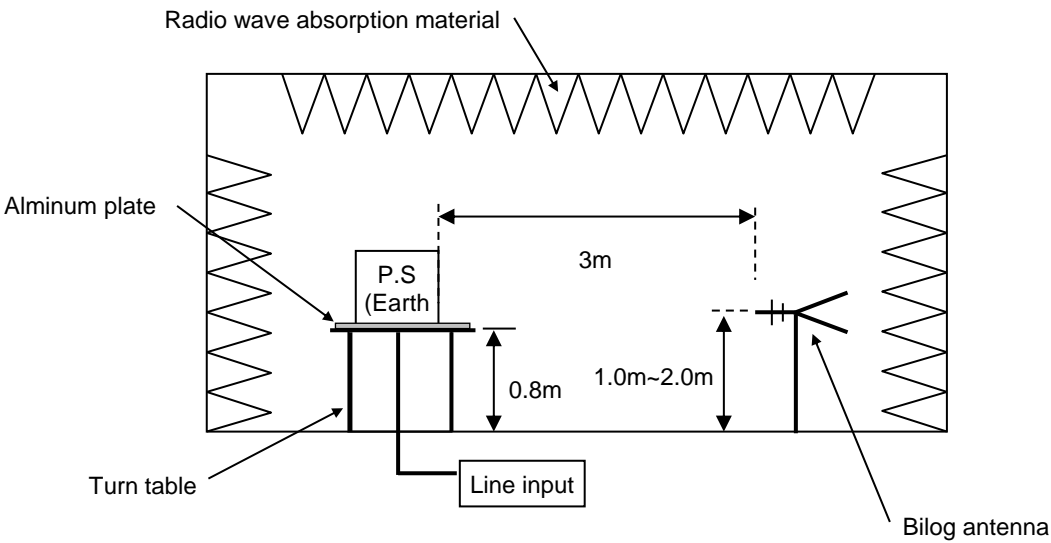
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
118.054	V	Stable	30.7	50	19.3	Pass	120.2	0		
189.628	V	Stable	34.7	50	15.3	Pass	100.2	24.7		
189.661	H	Stable	35.4	50	14.6	Pass	199.7	158.1		

DATA SHEET		Date	28-Feb-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	H.Sawayama

1. Line conduction



2. Radiated emission



Conditions

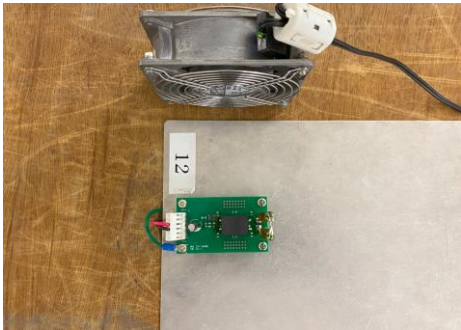
Test : EMI
Model Name: MUS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

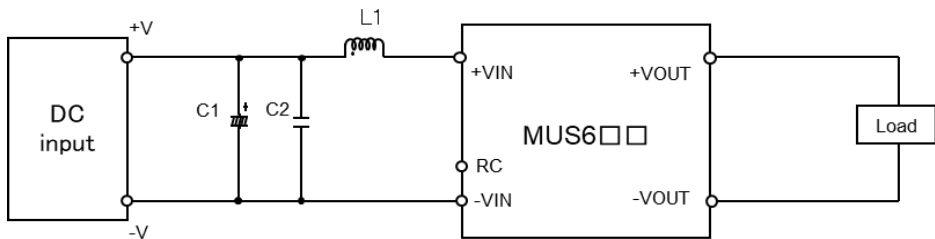


Fig.1 MUS6□□ Testing circuitry

C1 :	MUS605□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS612□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS624□	—	
	MUS648□	—	
C2 :	MUS605□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS612□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS624□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS648□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS605□	6500mA 1.5 μ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUS612□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS624□	2600mA 10 μ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUS648□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)